

Latest News - September 2009

Newsletter highlights

- Accel-RF to exhibit at EuMW Conference in Rome and CSIC Symposium in Greensboro, NC.
- Accel-RF announces successful delivery of first Millimeter-Wave Reliability Test System.
- Accel-RF Exhibits at CS ManTech 2009!- New HiPR fixtures and cooling methods on display.
- New high power Solid State Power Amplifier : +40 dBm at the DUT!

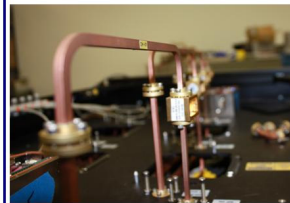
Accel-RF Delivers first Millimeter-Wave Reliability Test System!

Accel-RF delivers new Automated Accelerated Life-Test System (AARTS) for Millimeter-Wave Reliability Testing applications. This capability offers an excellent solution for in-situ high temperature life-test and performance characterization on devices that require RF power presented to the device in the 30 GHz to 90 GHz range. The first installation is for a military component research customer. The system, testing at frequencies of 58 GHz to 62 GHz with input power to the device of +17 dBm, can simultaneously test 8 devices at independent temperatures up to 250°C.

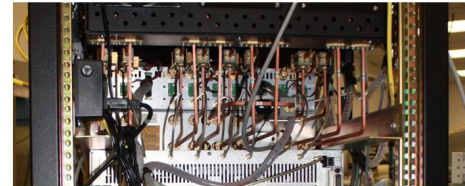
MMW Features:

- 8 & 16 Channel Systems
- Standard models up to 62 GHz
- Up to 100 Volts and 3 Amps DC Bias supply
- Up to 2 Watts device RF output power
- Integrated Bias conditioning networks for stability and DC blocking

Accel-RF



60 GHz System Checkout



Accel-RF Exhibiting at International Shows

Accel-RF will be exhibiting at EuMW Conference in Rome Sept. 29 - Oct. 1 and will be a silver sponsor at the CSIC symposium in Greensboro, NC Oct. 12-14.

Please come by our booth and get a personalized presentation of all of our new products and features.

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Accel-RF Exhibits Active Cooling RF Rel System at CS ManTech 2009

Lifetesting just got cooler!

At the recent Compound Semiconductor Manufacturing Technology Conference (CS ManTech) in Tampa, Florida, Accel-RF had a complete top section of our High Power Automated Accelerated Reliability Test System (**HiPR-AARTS**) on display. Accel-RF has an air-cooled and a liquid-cooled version of the active temperature-controlled system.

Typical performance of the air-cooled DUT chamber can achieve baseplate temperatures of $<50^{\circ}\text{C}$ for power dissipation of 60Watts and the liquid-cooled DUT chamber can achieve baseplate temperatures of $<15^{\circ}\text{C}$ for device power dissipation of 200Watts.



High Power – 200W RF, 400WDC
Active Cooling Sub-System on
Display

THE 2-BAY AARTS SYSTEM

Accel-RF offers both complete RF/DC and DC-only accelerated life test systems. Complete RF stimulus and monitoring for true in-situ RF/DC/Thermal reliability testing in a robust, fully integrated, turnkey system. The Accel-RF system can integrate and control a semiconductor parameter analyzer, take transistor characterization curves, and then extract and analyze parameters with our embedded analysis software. Perform Lognormal, Weibull, Exponential Analysis, Activation Energy Extraction, and more! Accel-RF has sales and service in Austria, Belgium, France, Germany, Italy, Japan, Netherlands, Switzerland, Taiwan and USA.

Email info@accelrf.com for more information.



New High Power Solid State Power Amplifier - +40 dBm at the DUT!

Accel-RF has shipped a new high power 8-channel Solid State Power Amplifier capable of delivering +40 dBm (10 Watts) of RF Power to the device under test over the frequency range of 3.0 GHz to 3.3 GHz and 1.0 GHz to 2.0 GHz. These SSPA units are being used to test high power devices for communications and radar applications. The SSPA rack-mount units can be integrated with Accel-RF's pulse systems for pulse-performance characterization testing.

Accel-RF has a wide range of solid state power amplifier options for our industry leading turn-key RF Reliability Testing System.

